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Symplement:Network CameraBrand Name /Trade Mark:SAMSUNGType designation /model:SND-5083PApplicant:SAMSUNG TECHWIN CO., LTD.In accordance with the following June 2004/108/ECThe Electromagnetic Compatibility Directive1004/108/ECThe Electromagnetic Compatibility Directive11/65/EURestriction of the use of certain hazardous substances in electrical and electronic equipment (recast)2011/65/EURestriction of the use of certain hazardous substances in electrical and electronic equipment (recast)2011/65/EULimits and methods of measurement of radio disturbance characteristics of information technology equipmentEN 55022:2010Limits and methods of measurement of radio disturbance characteristics of 			
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Title : Principal Research Engineer Signature :	Place and date of issue:		
Signature :	Authorized Signatory:	Name : Jei Soon, Kang	
		Title : Principal Research Engineer	
		Signature :	
		Braft	



Report No.: EMC-CE-4125 Page: 1 of 54

EMC TEST REPORT

Test report No	:	EMC-CE-4125
Type of Equipment	:	Network Camera
Type of Equipment	•	Network Camera
Model Name	:	SND-5083P
Applicant	:	Samsung Techwin Co., Ltd.
		#42 Seongju-Dong, Changwon-Shi,
		Kyungsangnam-Do, Korea
Manufacturer #1	:	Samsung Techwin Co., Ltd.
		#42 Seongju-Dong, Changwon-Shi,
		Kyungsangnam-Do, Korea
Manufacturer #2	:	TIANJIN SAMSUNG TECHWIN
		OPTO-ELECTRONIC CO., LTD
		No.11 Weiliu Road. Micro-Electronic Industrial
		Park Jingang Road Tianjin 300385, China
Test standards	:	EN 55022:2010, Class A
		EN 50130-4:2011
Testing Laboratory	:	EMC Compliance Ltd.
Test result	:	Complied

This product complies with the requirements of the EMC Directive 2004/108/ EC. The results in this report apply only to the sample tested.

This test report shall not be reproduced, except in full, without the written approval of EMC compliance Laboratory.

Date of receipt: 2013. 06. 10

Date of testing: 2013. 06. 17 ~ 06. 19



Issued date: 2013. 06. 26
Approved by:
YEOM, HAN-SEOK



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Report No.: EMC-CE-4125 Page: 3 of 54

1. Applicant information

Applicant:	SAMSUNG TECHWIN CO., LTD.	
Address:	#42 Seongju-Dong, Changwon-Shi,	
	Kyungsangnam-Do, Korea	
Telephone:	+82-70-7147-8361	
Fax:	+82-31-277-2784	
E-mail:	js2002.kang@samsung.com	
Contact name:	Kang Jei Soon	
Manufacturer#1:	SAMSUNG TECHWIN CO., LTD.	
Manufacturer#1: Address:	SAMSUNG TECHWIN CO., LTD. #42 Seongju-Dong, Changwon-Shi,	
	#42 Seongju-Dong, Changwon-Shi,	
Address:	#42 Seongju-Dong, Changwon-Shi, Kyungsangnam-Do, Korea	
Address: Telephone:	#42 Seongju-Dong, Changwon-Shi, Kyungsangnam-Do, Korea +82-70-7147-8361	
Address: Telephone: Fax:	#42 Seongju-Dong, Changwon-Shi, Kyungsangnam-Do, Korea +82-70-7147-8361 +82-31-277-2784	

Manufacturer#2:	TIANJIN SAMSUNG TECHWIN OPTO-ELECTRONIC CO., LTD
Address:	No.11 Weiliu Road. Micro-Electronic Industrial Park
	Jingang Road Tianjin 300385, China



2. Laboratory information

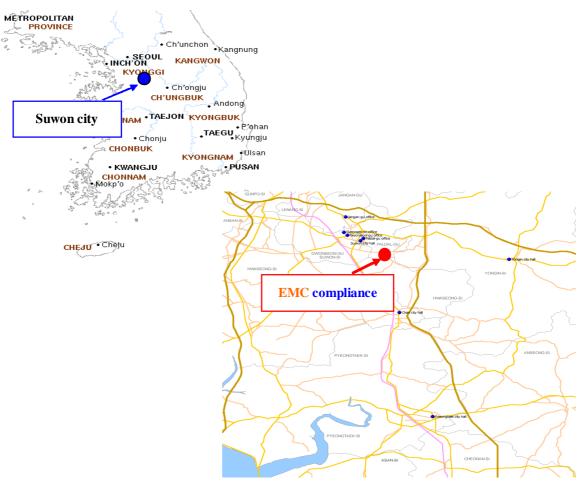
Address

EMC compliance Ltd.

480-5 Sin-dong, Yeongtong-gu, Suwon-city, Gyeonggi-do, 443-390, Korea Telephone Number: 82 31 336 9919 Facsimile Number: 82 505 299 8311

FCC CAB.: KR0040 VCCI Registration No. : R-3327, G-198, C-3706, T-1849 Industry Canada Registration No. : 8035A KOLAS NO.: 231

SITE MAP





3. Test system configuration

3.1 Operation environment

		Temperature	Humidity	Pressure	
Chamber(10 m)	:	26 °C	39 % R.H.	-	
Shielded room(CE)	:	28 °C	36 % R.H.	-	
Shielded room(ESD)	:	26 °C	48 % R.H.	99.5 kPa	

Test site

These testing items were performed following locations;

Test item	Test site
Conducted Emission	Shielded Room
Radiated Emission	10 m Chamber
Harmonics current	Immunity area
Voltage fluctuations and flickers	Immunity area
Electrostatic discharge	Shielded Room
Radiated RF immunity	Fully anechoic chamber (3 m)
Electric Fast Transient/BURST	Shielded Room
Surge	Shielded Room
Conducted RF immunity	Shielded Room
Voltage dip/interruption	Shielded Room
Mains supply voltage variations	Shielded Room



3.2 Measurement Uncertainty

All measurements involve certain levels of uncertainties, especially in field of EMC. The factors contributing to uncertainties are test receiver, cable loss, antenna factor calibration, Antenna directivity, antenna factor variation with height, antenna phase center variation, antenna frequency interpolation, measurement distance variation, site imperfection, mismatch, and system repeatability. Based on CISPR 16-4-2, the measurement uncertainty level with a 95 % confidence level was applied.

Conducted emission measurement (C.L: Approx 95 %, $k = 2$)		
Shielded Room (CE#1)	9 kHz ~ 150 kHz: ± 3.82 dB	
	150 kHz ~ 30 MHz: ± 3.4	43 dB
Shielded Room (CE#2)	9 kHz ~ 150 kHz: ± 3.8	2 dB
	150 kHz ~ 30 MHz: ± 3.4	43 dB
Shielded Room (CE#3)	9 kHz ~ 150 kHz: ± 4.0	
	150 kHz ~ 30 MHz: ± 3.0	63 dB
Radiated Emission measurement	t (C.L: Approx 95 %, k =	= 2)
	30 MHz ~ 300 MHz	3 m: + 4.56 dB, - 4.58 dB
		10 m: + 4.56 dB, - 4.56 dB
10 m Chamber (#F4)	300 MHz ~1 000 MHz	3 m: + 4.84 dB, - 4.85 dB
		10 m: + 4.71 dB, - 4.72 dB
	1 GHz ~ 6 GHz	3 m: + 6.19 dB, - 6.20 dB
	30 MHz ~ 300 MHz	3 m: + 4.86 dB, - 4.88 dB
		10 m: + 4.86 dB, - 4.86 dB
10 m Chamber (#F2)	300 MHz ~1 000 MHz	3 m: + 4.98 dB, - 4.99 dB
		10 m: + 4.85 dB, - 4.87 dB
	1 GHz ~6 GHz	3 m: + 6.19 dB, - 6.20 dB
Radio Frequency Electromagnetic Fields (C.L: Approx 95 %, $k = 2$)		
± 1.82 dB		
Disturbance power Electromagnetic Fields (C.L: Approx 95 %, $k = 2$)		
± 3.73 dB		



4. Description of E.U.T.

4.1 General information

Video	
Imaging Device	1/3" 1.3M PS CMOS
Total Pixels	1,384(H) x 1,076(V)
Effective Pixels	1,329(H) x 1,049(V)
Scanning System	Progressive
Min. Illumination	Color : 0.05 Lux (1/30sec, F1.2, 50IRE), 0.0008Lux (2sec, 50IRE) B/W : 0.005 Lux (1/30sec, F1.2, 50IRE)
S / N Ratio	50dB
Video Out	CVBS : 1.0 Vp-p / 75Ω composite, 720x480(N), 720x576(P), for installation - DIP connector type
Lens	
Focal Length (Zoom Ratio)	2.8~10mm
Max. Aperture Ratio	F1.2
Angular Field of View	H: 94.6°(Wide)~28.8°(Tele), V: 68.4°(Wide)~21.6°(Tele)
Min. Object Distance	0.5m
Focus Cotrol	Manual
Lens Type	DC Auto Iris
Mount Type	Board-in type
Pan / Tilt / Rotate	
Pan Range	0 ° ~ +354 °
Tilt Range	0 ° ~ +67 °
Rotate Range	0 ° ~ +355 °
Operational	
Camera Title	Off / On (Displayed up to 40 characters)
Day & Night	Auto (ICR) / Color / B/W / External / Schedule
Backlight Compensation	Off / BLC
Wide Dynamic Range	130dB 1
Contrast Enhancement	SSDR (Samsung Super Dynamic Range) (Off / On)
Digital Noise Reduction	SSNRIII (2D+3D Noise Filter) (Off / On)
Digital Image Stabilization	Off / On
Defog	Auto/Manual/Off
Motion Detection	Off / On (4ea 4 Points Polygonal zones)
Privacy Masking	Off / On (32ea Rectangular zones)
Gain Control	Off / Low / Middle / High
White Balance	ATW / AWC / Manual / Indoor / Outdoor
Electronic Shutter Speed	Minimum / Maximum / Anti flicker (2 ~ 1/12,000sec)
Digital Zoom	Off / On
Flip / Mirror	Off / On
Intelligent Video Analytics	Tampering, Virtual Line, Enter/Exit, Appear / Disappear, Audio Detection, Face Detection
Alarm I/O	Input 1ea / Output 1ea
Audio In	Selectable (Mic IN/Line IN), Max output level: 1 Vrms
Audio In	Supply voltage: 2.5VDC(4mA), Input impedance: approx. 2K Ohm
Audio out	Line out (3.5mm stereo mini jack)
Alarm Triggers	Motion detection, Tampering, Audio Detection, Face Detecton, Video Analytics, Alarm Input, Network Disconnection
Alarm events	File upload via FTP and E-Mail Notification via E-Mail, TCP and HTTP local storage(SD/SDHC/SDXC) recording at Network disconnected & Event (Alarm Triggers) External output



Matural		
Network		
Ethernet	RJ-45 (10/100BASE-T)	
Video Compression Format	H.264 (MPEG-4 Part 10/AVC), Motion JPEG	
Resolution	1280x1024, 1280x720P(HD), 1024x768, 800x600, 640x480, 320x240	
Max. Framerate	H.264 : Max 60fps at all resolutions Motion JPEG : 1280x1024 / 1280x720 / 1024x768 : Max. 15 fps 800x600 / 640x480 / 320x240 : Max. 30fps	
Video Quality Adjustment	H.264 : Compression Level, Target Bitrate Level Control MJPEG : Quality Level Control	
Bitrate Control Method	H.264 : CBR or VBR MJPEG : VBR	
Streaming Capability	Multiple Streaming (Up to 10 Profiles)	
Audio Compression Format	G.711 u-law /G.726 Selectable G.726 (ADPCM) 8KHz, G.711 8KHz G.726 : 16Kbps, 24Kbps, 32Kbps, 40Kbps	
Audio Communication	Bi-directional	
IP	IPv4, IPv6	
Protocol	TCP/IP, UDP/IP, RTP(UDP), RTP(TCP), RTCP,RTSP, NTP, HTTP, HTTPS, SSL, DHCP, PPPoE, FTP, SMTP, ICMP, IGMP, SNMPv1/v2c/v3(MIB-2), ARP, DNS, DDNS, QoS, PIM-SM, UPnP, Bonjour	
Security	HTTPS(SSL) Login Authentication Digest Login Authentication IP Address Filtering User access Log 802.1x Authentication	
Streaming Method	Unicast / Multicast	
Max. User Access	15 users at Unicast Mode	
Memory Slot	SD/SDHC/SDXC - motion Images recorded in the SD/SDHC/SDXC memory card can be downloaded.	
Application Programming Interface	ONVIF Profile S & G HTTP API v2.0 SVNP 1.2	
Web Language	English, French, German, Spanish, Italian, Chinese, Korean, Russian, Japanese, Swedish, Denish, Portuguese, Turkish, Polish, Czech, Rumanian, Serbian, Dutch, Croatia, Hungary, Greek, Finnish, Norwegian	
Web Viewer	Supported OS : Windows XP / VISTA / 7 / 8, MAC OS X 10.7 Supported Browser : Microsoft Internet Explorer (Ver. 7~10), Mozilla Firefox (Ver. 9~19), Google Chrome (Ver. 15~25), Apple Safari (Ver. 6.0.2(Mac OS X 10.8, 10.7 Only), 5.1.7) * Mac OS X Only	
Central Management Software	SmartViewer 4.0	



Environmental	
Operating Temperature / Humidity	-10°C ~ +55°C(+14°F ~ +131°F) / Less than 90% RH
Storage Temperature / Humidity	-30°C ~ +60°C (-22°F ~ +140°F) / Less than 90% RH
Electrical	
Input Voltage / Current	DC12V±10%, PoE(IEEE802.3af,Class3)
Power Consumption	Max. 9.0W (DC 12V) Max. 11.0W(PoE, Class3)
Mechanical	
Color / Material	IVORY(Plastic)
Dimension	D132.1 ,H107.6
Weight	505g



4.2 Product description

Type of product	Network Camera
Model name (Basic)	SND-5083P
Model name (Variant)	-
Difference	-
Trade name	-
Serial no	Engineering Sample
Testing voltage	DC 12 V, PoE
Product rating	DC 12 V, PoE
Internal clock frequency	Above 108 Mz
Note	* AC/DC adaptor was not provided by the manufacturer.* PoE Switch was not provided by the manufacturer.

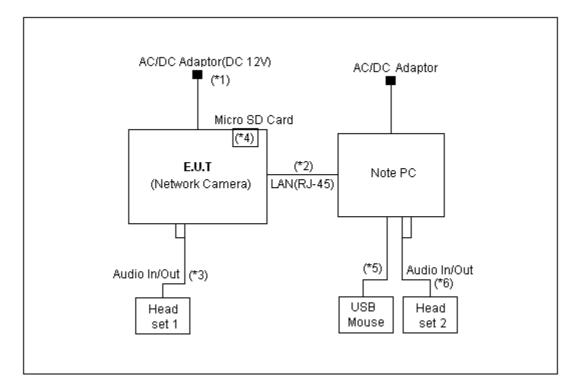
4.3 Auxiliary equipments

Type Model / Part #		Serial number	Manufacturer	
Note PC	Note PC SPARQ M53V		HanSung computer	
Headset 1	SHS-250V	-	SAMSUNG	
Headset 2 SHS-250V		-	SAMSUNG	
USB Mouse	1088	8165906050949	Microsoft	
Micro SD Card (4GB)	-	-	SanDisk	
AC/DC Adaptor (DC 12V)	DAD 12050DKA	-	Dream Electronic	
PoE Switch	FS108P	1DL20C3K00541	NETGEAR	



4.4 Test configuration

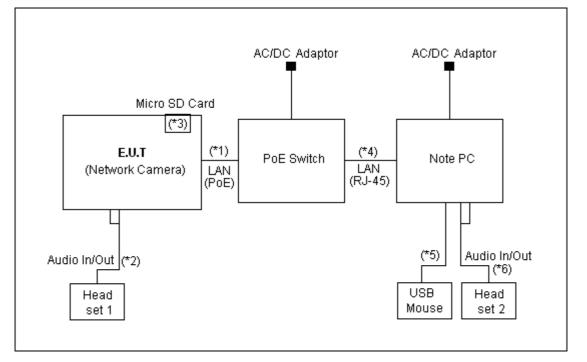
#1- DC 12V



Note	Start		En	Cable			
*	Name	I/O port	Name	I/O port	Length (m)	Spec.	Cable
1		Power	AC/DC Adaptor	Power	2.0	Non-Shield	-
2	EUT (Network	LAN(RJ-45)	Note PC	LAN(RJ-45)	3.0	Non-Shield	-
3	Camera)	Audio In/Out	Headset 1	Audio In/Out	2.0	Non-Shield	-
4		Micro SD Card	1 Micro SD Card Micro SD Ca		Direct	-	-
5	Note PC	USB	USB Mouse	USB	1.8	Shield	-
6	Note PC	Audio In/Out	Headset 2	Audio In/Out	2.0	Non-Shield	-



#2- PoE



* Power supplied from PoE Switch

Note		Start	En	d	Cable			
*	Name	I/O port	Name	I/O port	Length (m)	Spec.	Cable	
1	EUT	EUT LAN(PoE) PoE Switch LAN		LAN(PoE)	3.0	Non-Shield	-	
2	(Network	Audio In/Out	Headset 1	Audio In/Out	2.0	Non-Shield	-	
3	Camera)	Camera) Micro SD Card Micro SD Card		Micro SD Card	Direct	-	-	
4		LAN(RJ-45)	PoE Switch	LAN(RJ-45)	3.0	Non-Shield	-	
5	Note PC	USB	USB Mouse	USB	1.8	Shield	-	
6		Audio In/OutHeadset 2A		Audio In/Out	2.0	Non-Shield	-	

4.5 Operating conditions

The EUT was configured as normal intended use.

Test mode	Normal operating
1	Camera monitoring test. (Web view)

* Note: 2 types of powers are available for the product, that are DC 12 $\,$ V, PoE.

Therefore, tests were performed for 2 different types of powers.



5. Summary of test results

5.1 Summary of EMI emission test results

Applied	Test items	Test method	Result
\square	Conducted Emission	EN 55022:2010	Complied
\square	Radiated Emission	EN 55022:2010	Complied
	Harmonics current	EN 61000-3-2:2006+A2:2009	N/A
	Voltage fluctuations and flickers	EN 61000-3-3:2008	N/A

5.2 Summary of immunity test results

Applied	Test items	Test method	Result					
* EN 50130-4:2011								
\boxtimes	Electrostatic discharge	EN 61000-4-2:2009	Complied					
\square	Radiated RF immunity	EN 61000-4-3:2006+A2:2010	Complied					
\square	Electric Fast Transient/BURST	EN 61000-4-4:2004+A1:2010	Complied					
\square	Surge	EN 61000-4-5:2006	Complied					
\square	Conducted RF immunity	EN 61000-4-6:2009	Complied					
	Voltage dip/interruption	EN 61000-4-11:2004	N/A					
	Mains supply voltage variations	EN 50130-4:2011	N/A					



5.3 Performance criteria

The variety and the diversity of the apparatus within the scope of this document makes it difficult to define precise criteria for the evaluation of the immunity test results. If as a result of the application of the tests defined in this standard, the apparatus becomes dangerous or unsafe then the apparatus shall be deemed to have failed the test. A functional description and a definition of performance by the manufacture and noted in the test report, based on the following criteria:

Electrostatic discharge

There shall be no damage, malfunction or change of status due to the conditioning. Flickering of an indicator during the application of discharge is permissible, providing which could be interpreted by associated equipment as a change,

Radiated electromagnetic fields

There shall be no damage, malfunction or change of status due to the conditioning. Flickering of an indicator during the application of discharge is permissible, providing which could be interpreted by associated equipment as a change, and no such Flickering of indicators occurs at a field strength of 3 V/m. For components of CCTV systems, where the picture is allowed at 10 V/m, providing.

- (a) there is no permanent damage or change to EUT
 - (e.g. no corruption of memory or changes to programmable setting etc.)
- (b) at 3 V/m, any deterioration of the picture is so minor that the system could still be used; and
- (c) there is no observable deterioration of the picture at 1 $\,\rm V/m.$

Fast transient burst / slow high energy voltage surge

There shall be no damage, malfunction or change of status due to the conditioning. Flickering of an indicator during the application of discharge is permissible, providing That there is no residual is permissible, providing that there is no residual change in the EUT or any change in outputs, which could be interpreted by associated equipment as



Conducted RF immunity

There shall be no damage, malfunction or change of status due to the conditioning. Flickering of an indicator during the application of discharge is permissible, providing That there is no residual is permissible, providing that there is no residual change in the EUT or any change in outputs, which could be interpreted by associated equipment as a change, and no such flickering of indicators oeuvres at $U = 130 \text{ dB}\mu N$. For component of CCTV systems, where the status is monitored by observing the TV picture, then deterioration of the picture is allowed at $U = 140 \text{ dB}\mu N$, providing:

- (a) there is no permanent damage or change to the EUT(e.g. no corruption of memory or changes to programmable settings etc.)
- (b) at $U = 130 \text{ dB}\mu V$, any deterioration of the picture is so minor that the system could still be used; and
- (c) there in no observable deterioration of the picture at U = 120 dB μ N.

Voltage dip/interruption / Voltage variation

There shall be no damage, malfunction or change of status due to the conditioning.

Flickering of an indicator during the conditioning is permissible, providing that there is no residual change in the EUT or any change in outputs, which could be interpreted by associated equipment as a change. The EUT shall meet the acceptance criteria for the functional test, after the conditioning.



6. Test results

6.1 Conducted Emission

Test specification	EN 55022:2010, Class A					
Testing voltage	DC 12 V, PoE					
Test facility	Shielded room (CE#2)					
Date	2013. 06. 17	2013. 06. 17				
Temperature (°C)	28 °C	Humidity (% R.H.)	36 % R.H.			
Remarks	Complied					

6.1.1 Limits of conducted emission measurement

AC main

Frequency	Class A	(dB(µN))	Class B (dB(μN))		
[MHz]	Quasi-peak	Average	Quasi-peak	Average	
0.15 ~ 0.5	79	66	66 ~ 56 *	56 ~ 46*	
0.5 ~ 5	73	60	56	46	
5 ~ 30	73	60	60	50	

*The limit decreases linearly with the logarithm of frequency.

⊠ Telecommunication

Frequency	Class A Voltage	Limits (dB(μN))	Current Limits (dB(µA))		
[MHz]	Quasi-Peak Average		Quasi-Peak	Average	
0.15 ~ 0.5	97 to 87	97 to 87 84 to 74		40 to 30	
0.5 ~ 30	87	74	43	30	
Frequency	Class B Lin	nits (dB(µV))	Current Limits (dB(µA))		
[MHz]	Quasi-Peak	Average	Quasi-Peak	Average	
0.15 ~ 0.5	84 to 74	74 to 64	40 to 30	30 to 20	
0.5 ~ 30	74	64	30	20	

* The limits decrease linearly with the logarithm of the frequency in the range 0.15 $\,$ Mz to 0.5 $\,$ Mz

* The current and voltage disturbance limits are derived for use with an impedance stabilization Network (ISN) which presents a common mode (asymmetric mode) impedance of 150 Ω to the telecommunication port under test (conversion factor is 20 log₁₀ 150/I = 44 dB).



6.1.2 Measurement procedure

The measurements were performed in a shielded room. EUT was setup as shown in photograph and placed on a non-metallic table height of 0.8 m above the reference ground plane. The rear of table was located 0.4 m to the vertical conducted plane. EUT was power through the LISN, which was bonded to the ground plane. The LISN power was filtered. Each EUT power lead, except ground (safety) lead was individually connected through a LISN to input power source. EUT signal cables that hung closer than 0.4 m to the Horizontal metal ground 0.3 m ~ 0.4 m long. The power cord was bundles in the center. All peripheral equipment was powered from a sub LISN. The LISN and ISN were positioned 0.8 m from the EUT. Peak and Average detection were used in preliminary testing and Quasi-peak and Average detections were used at final measurement. Both lines of power cord, hot and neutral, were measured.

Equipment	Model	Serial No.	Makers	Next Cal. Date	Used
Test Receiver	ESHS30	844827/011	R&S	2013.08.06	
Test Receiver	ESCI7	100732	R&S	2014.02.18	
Test Receiver	ESCI	100001	R&S	2013.07.10	
Test Receiver	ESCI	100710	R&S	2013.11.06	\boxtimes
LISN	ENV216	101352	R&S	2014.01.07	\boxtimes
LISN	L3-32	0120J20305	PMM	-	\boxtimes
8-WIRE ISN	NTFM 8158 CAT5	CAT5-8158-0028	SCHWARZBECK	2014.04.13	\boxtimes
8-WIRE ISN	NTFM 8158 CAT3	CAT3-8158-0020	SCHWARZBECK	2014.04.13	\boxtimes
ISN	ST08	24342	TESEQ	2014.06.21	
ISN	ENY81	101545	R&S	2013.08.29	

6.1.3 Used equipments



6.1.4 Photographs of test setup

- * Telecommunication
- #1- DC 12V



#2-PoE

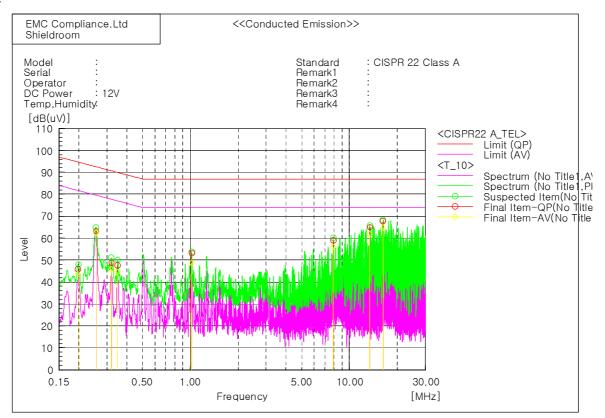




6.1.5 Conducted emission measurement result

* Telecommunication port

#1- DC 12V _ LAN Port (LCL 55 dB)_10 Mbps (SND-5083P)

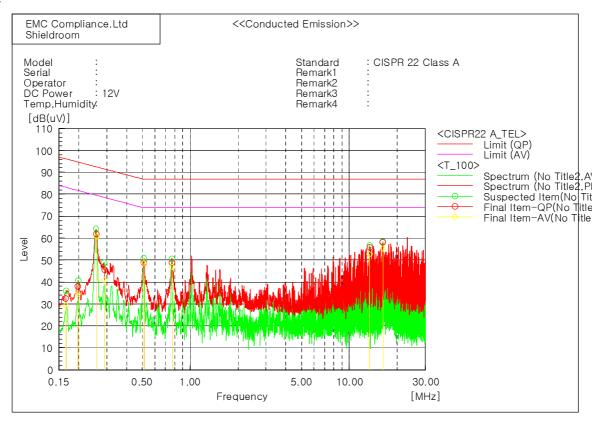


Final Result

	No Title1 P	hase								
No.	Frequency	Reading	Reading	c.f	Result	Result	Limit	Limit	Margin	Margin
		QP	CAV		QP	CAV	QP	AV	QP	CAV
	[MHz]	[dB(uV)]	[dB(uV)]	[dB]	[dB(uV)]	[dB(uV)]	[dB(uV)]	[dB(uV)]	[dB]	[dB]
1	0.19762	35.4	33.2	10.4	45.8	43.6	94.7	81.7	48.9	38.1
2	0.25703	53.0	52.3	10.2	63.2	62.5	92.5	79.5	29.3	17.0
3	0.32109	38.7	35.7	10.1	48.8	45.8	90.7	77.7	41.9	31.9
4	0.34978	37.4	34.4	10.1	47.5	44.5	90.0	77.0	42.5	32.5
5	1.02271	43.4	38.8	9.9	53.3	48.7	87.0	74.0	33.7	25.3
6	7.9228	49.3	46.3	9.7	59.0	56.0	87.0	74.0	28.0	18.0
7	13.4192	55.4	52.2	9.6	65.0	61.8	87.0	74.0	22.0	12.2
8	16.22832	58.2	55.1	9.6	67.8	64.7	87.0	74.0	19.2	9.3



#1- DC 12V _ LAN Port (LCL 65 dB)_100 Mbps(SND-5083P)

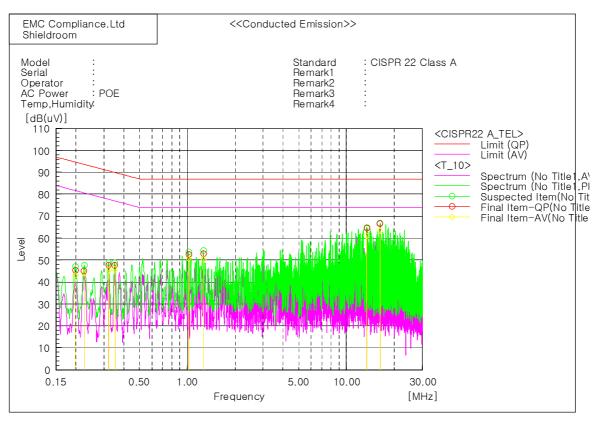


Final Result

	No Title2 P	hase								
No.	Frequency	Reading	Reading	c.f	Result	Result	Limit	Limit	Margin	Margin
	[]	QP	CAV	[10]	QP	CAV	QP LID(L)()	AV	(QP)	ÇAV
	[MHz]	[dB(uV)]	[dB(uV)]	[dB]	[dB(uV)]	[dB(uV)]	[dB(uV)]	[dB(uV)]	[dB]	[dB]
1	0.16604	22.2	19.0	10.3	32.5	29.3	96.2	83.2	63.7	53.9
2	0.19807	27.9	24.4	10.2	38.1	34.6	94.7	81.7	56.6	47.1
3	0.25906	51.7	50.6	10.1	61.8	60.7	92.5	79.5	30.7	18.8
4	0.29042	35.5	30.7	10.1	45.6	40.8	91.5	78.5	45.9	37.7
5	0.51328	39.0	38.8	9.9	48.9	48.7	87.0	74.0	38.1	25.3
6	0.77204	38.9	36.8	9.9	48.8	46.7	87.0	74.0	38.2	27.3
7	13.41893	46.1	42.9	9.7	55.8	52.6	87.0	74.0	31.2	21.4
8	16.22865	48.3	45.6	9.7	58.0	55.3	87.0	74.0	29.0	18.7



#2- PoE _ LAN Port (LCL 55 dB)_10 Mbps(SND-5083P)

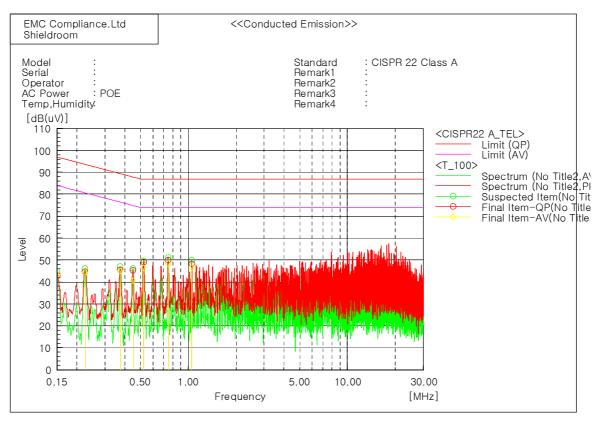


Final Result

	No Title1 P	hase								
No.	Frequency	Reading	Reading	c.f	Result	Result	Limit	Limit	Margin	Margin
	[10] [1	QP		[]	QP				QP	CAV
	[MHz]	[dB(uV)]	[dB(uV)]	[dB]	[dB(uV)]	[dB(uV)]	[dB(uV)]	[dB(uV)]	[dB]	[dB]
1	0.19845	35.0	32.6	10.4	45.4	43.0	94.7	81.7	49.3	38.7
2	0.22529	34.7	33.5	10.3	45.0	43.8	93.6	80.6	48.6	36.8
3	0.32082	37.5	35.3	10.1	47.6	45.4	90.7	77.7	43.1	32.3
4	0.35081	37.6	35.6	10.1	47.7	45.7	89.9	76.9	42.2	31.2
5	1.02286	42.6	40.6	9.9	52.5	50.5	87.0	74.0	34.5	23.5
6	1.26702	43.1	40.5	9.9	53.0	50.4	87.0	74.0	34.0	23.6
7	13.4195	54.9	51.5	9.6	64.5	61.1	87.0	74.0	22.5	12.9
8	16.22821	56.9	53.7	9.6	66.5	63.3	87.0	74.0	20.5	10.7



#2- PoE _ LAN Port (LCL 65 dB)_100 Mbps(SND-5083P)



Final Result

	No Title2 P	hase								
No.	Frequency	Reading	Reading	c.f	Result	Result	Limit	Limit	Margin	Margin
		QP	CAV		QP	CAV	QP	AV	QP	CAV
	[MHz]	[dB(uV)]	[dB(uV)]	[dB]	[dB(uV)]	[dB(uV)]	[dB(uV)]	[dB(uV)]	[dB]	[dB]
1	0.15039	32.7	33.0	10.3	43.0	43.3	97.0	84.0	54.0	40.7
2	0.22553	34.5	34.2	10.2	44.7	44.4	93.6	80.6	48.9	36.2
3	0.3744	35.7	35.0	10.0	45.7	45.0	89.4	76.4	43.7	31.4
4	0.4502	35.3	30.6	10.0	45.3	40.6	87.9	74.9	42.6	34.3
5	0.52546	39.1	36.5	9.9	49.0	46.4	87.0	74.0	38.0	27.6
6	0.74902	40.0	38.5	9.9	49.9	48.4	87.0	74.0	37.1	25.6
7	1.05146	38.5	36.7	9.8	48.3	46.5	87.0	74.0	38.7	27.5



6.2 Radiated Emission

Test specification	EN 55022:2010, Class A						
Testing voltage	DC 12 V, PoE						
Test facility	10 m Chamber (#F2)						
Test distance	10 m,3 m	10 m, 3 m					
Date	2013. 06. 17						
Temperature (°C)	26 °C	Humidity (% R.H.)	39 % R.H.				
Remarks	Complied						

6.2.1 Limits of radiated emission measurement

\boxtimes Limits below 1 GHz

Frequency [Mtz]	Class A (dB($\mu N/m$)) @ 10 m	Class B (dB(µN/m)) @ 10 m
30 ~ 230	40	30
230 ~ 1 000	47	37

\boxtimes Limits above 1 GHz

Frequency	Class A	@ 3 m	Class B @ 3 m			
Frequency [GHz]	Average limit	Peak limit	Average limit	Peak limit		
LOIR	$(dB(\mu N/m))$	$(dB(\mu N/m))$	$(dB(\mu N/m))$	$(dB(\mu N/m))$		
1 ~ 3	56	76	50	70		
3~6	60	80	54	74		
Note - The lower lin	mit applies at the tran	sition frequency.				

6.2.2 Measurement procedure

The test was done at a 10 m chamber with a quasi-peak detector. EUT was placed on a non-metallic table height of 0.8 m above the reference ground plane. Cables were folded back and forth forming a bundle 0.3 m to 0.4 m long and were hanged at a 0.4 m height to the ground plane. Cables connected to EUT were fixed to cause maximum emission. Test was made with the antenna positioned in both the horizontal and vertical planes of polarization. The measurement antenna was varied in height above the conducting ground plane to obtain the maximum signal strength.



6.2.3 Used equipments

Equipment	Model no.	Serial no.	Makers	Next Cal. Date	Used
Test Receiver	ESCI7	100732	R&S	2014.02.18	\boxtimes
Test Receiver	ESCI	100001	R&S	2013.07.10	
Test Receiver	ESCI	100710	R&S	2013.11.06	
Bi-Log Antenna	VULB 9168	440	SCHWARZBECK	2013.10.04	\boxtimes
Amplifier	310N	293004	SONOMA INSTRUMENT	2013.11.06	\boxtimes
3 dB Attenuator	8491B	22981	HP	2014.03.19	\boxtimes
Antenna Mast	MA4000-EP	303	Innco Systems	-	\square
Turn Table	DT2000S-1t	079	Innco Systems	-	\square
Amplifier	8449B	3008A02343	AGILENT	2013.11.06	\square
Horn ANT	3115	00086706	ETS	2013.11.21	\square
Spectrum Analyzer	FSP7	100289	R&S	2013.12.14	

6.2.4 Sample calculation

The field strength is calculated adding the antenna Factor, cable loss and, Antenna pad adding,

subtracting the amplifier gain from the measured reading.

The sample calculation is as follow:

Result = M.R + C.F(A.F + C.L + 3 dB Att - A.G)

M.R = Meter Reading

C.F = Correction Factor

A.F = Antenna Factor

C.L = Cable Loss

A.G= Amplifier Gain

3 dB Att = 3 dB Attenuator

If M.R is 30 dB, A.F 12 dB, C.L 5 dB, 3 dB, A.G 35 dB

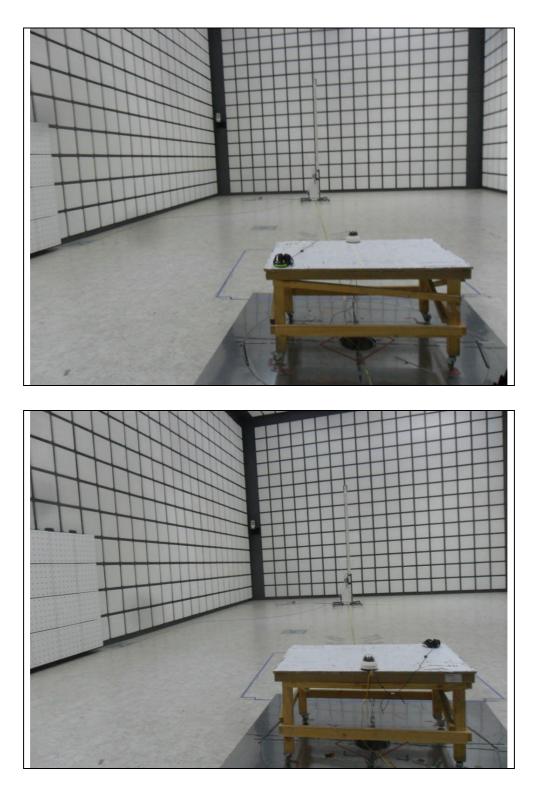
The result is

 $30 + 12 + 5 + 3 - 35 = 15 \text{ dB}(\mu N/m)$



6.2.5 Photographs of test setup

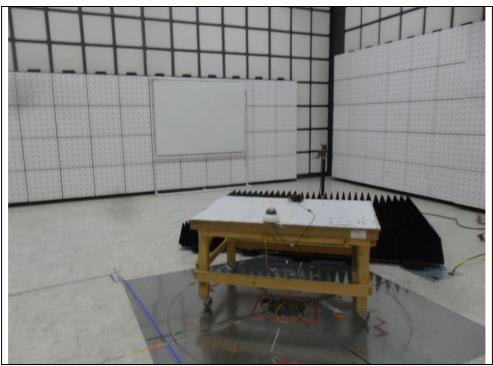
* 30 MHz ~ 1 GHz (#1- DC 12V)





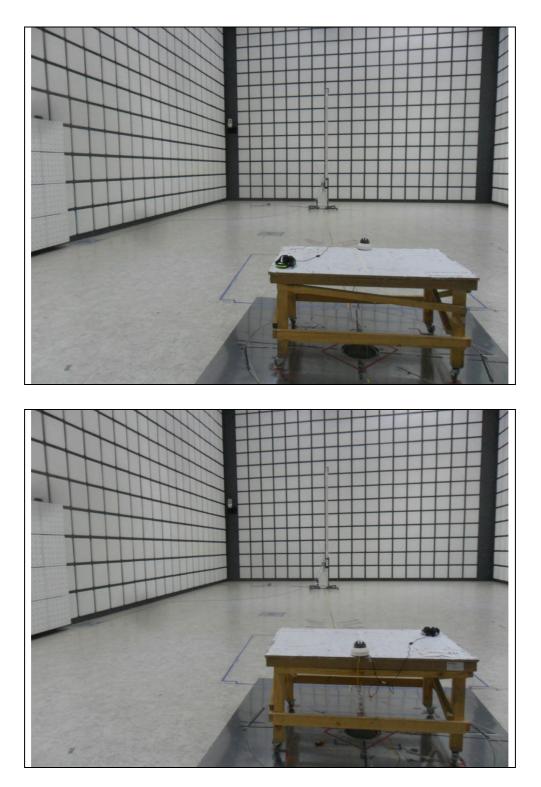
* 1 GHz ~ 6 GHz (#1- DC 12V)





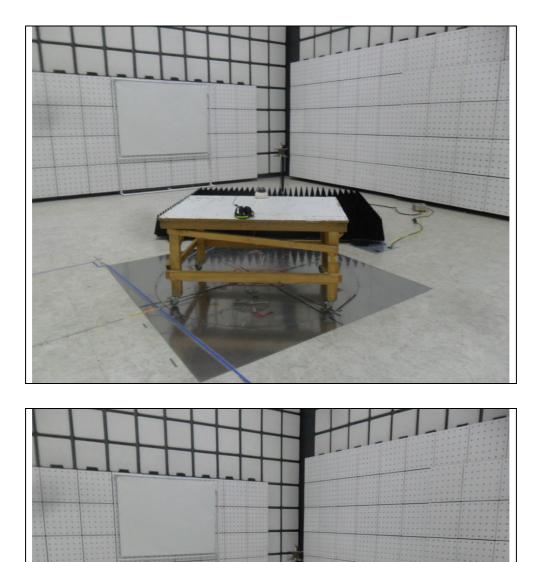


* 30 Mz ~ 1 GHz (#2-PoE)





* 1 GHz ~ 6 GHz (#2-PoE)

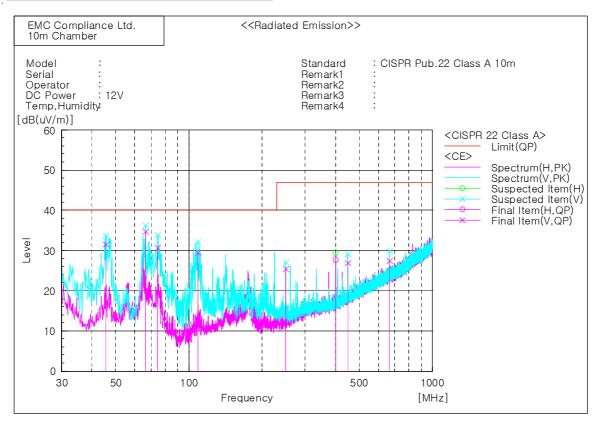




6.2.6 Radiated emission measurement result

* Graph and Data

* 30 Mz ~ 1 Gz (#1- DC 12V)_SND-5083P

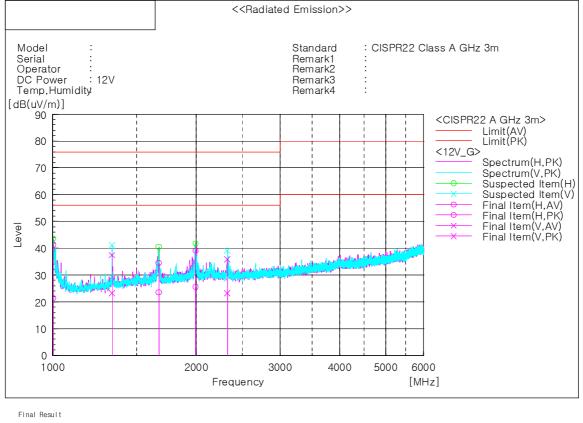


Final	Result

No.	Frequency	(P)	Reading	c.f	Result	Limit	Margin	Height	Angle	Remark
	[MHz]		QP [dB(uV)]	[dB(1/m)]	QP [dB(uV/m)]	QP [dB(uV/m)]	QP [dB]	[cm]	[deg]	
1	45.649	V	44.9	-13.4	31.5	40.0	8.5	100.0	280.7	
2	66.271	V	48.9	-14.2	34.7	40.0	5.3	100.0	208.6	
3	74.507	V	46.3	-15.7	30.6	40.0	9.4	100.0	187.6	
4	108.822	V	45.6	-16.2	29.4	40.0	10.6	100.0	2.9	
5	249.951	V	37.9	-12.5	25.4	47.0	21.6	100.0	40.6	
6	400.048	Н	35.2	-7.5	27.7	47.0	19.3	400.0	175.3	
7	450.017	V	32.8	-5.9	26.9	47.0	20.1	100.0	4.7	
8	666.079	V	28.3	-0.8	27.5	47.0	19.5	100.0	88.6	



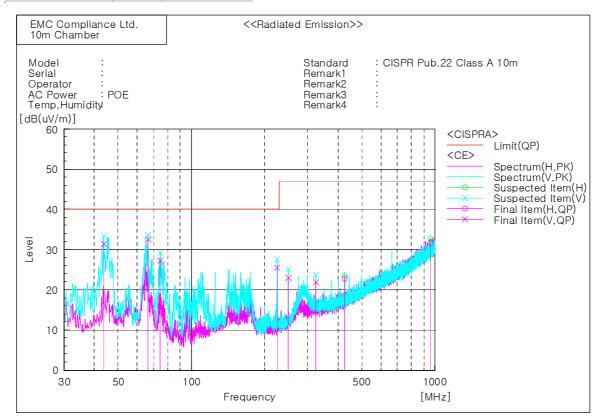
* 1 GHz ~ 6 GHz (#1- DC 12V) _ SND-5083P



No.	Frequency	(P)	Reading	Reading	c.f	Result	Result	Limit	Limit	Margin	Margin	Height	Angle	Remark
			AV	PK		AV	PK	AV	PK	AV	PK			
	[MHz]		[dB(uV)]	[dB(uV)]	[dB(1/m)]	[dB(uV/m)]	[dB(uV/m)]	[dB(uV/m)]	[dB(uV/m)]	[dB]	[dB]	[cm]	[deg]	
1	1003.125	Н	28.4	48.3	-7.0	21.4	41.3	56.0	76.0	34.6	34.7	100.0	22.1	
2	1331.875	V	29.0	43.1	-5.7	23.3	37.4	56.0	76.0	32.7	38.6	100.0	35.2	
3	1670.000	Н	26.9	37.9	-3.4	23.5	34.5	56.0	76.0	32.5	41.5	100.0	7.6	
4	1995.000	Н	27.2	40.7	-1.6	25.6	39.1	56.0	76.0	30.4	36.9	100.0	140.6	
5	2325.000	V	24.1	36.6	-0.8	23.3	35.8	56.0	76.0	32.7	40.2	100.0	123.4	



* 30 MHz ~ 1 GHz (#2-PoE) _ SND-5083P

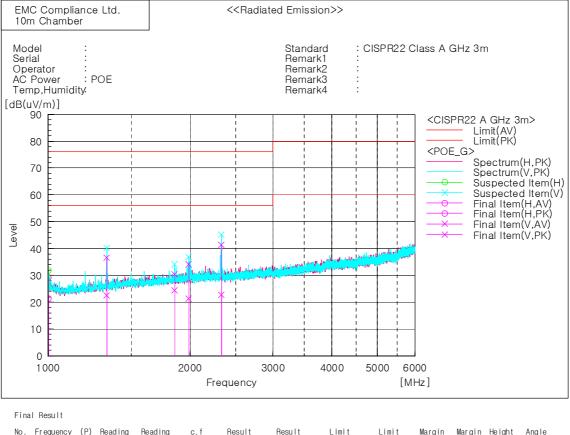


Final Result

No.	Frequency	(P)	Reading QP	c.f	Result QP	Limit QP	Margin QP	Height	Angle	Remark
	[MHz]		[dB(uV)]	[dB(1/m)]	[dB(uV/m)]	[dB(uV/m)]	[dB]	[cm]	[deg]	
1	43.832	V	44.9	-13.5	31.4	40.0	8.6	100.0	160.2	
2	66.257	V	46.7	-14.2	32.5	40.0	7.5	100.0	195.6	
3	74.512	V	43.0	-15.7	27.3	40.0	12.7	100.0	150.2	
4	224.979	V	39.3	-13.8	25.5	40.0	14.5	100.0	56.7	
5	249.956	V	35.5	-12.5	23.0	47.0	24.0	100.0	51.6	
6	325.012	V	31.4	-9.5	21.9	47.0	25.1	100.0	321.7	
7	425.038	Н	29.4	-6.6	22.8	47.0	24.2	400.0	244.6	
8	957.078	Н	26.3	5.4	31.7	47.0	15.3	400.0	181.7	



* 1 GHz ~ 6 GHz (#2- PoE) _ SND-5083P



No.	Frequency	(P)	Reading	Reading	c.f	Result	Result	Limit	Limit	Margin	Margin	Height	Angle
			AV	PK		AV	PK	AV	PK	AV	PK		
	[MHz]		[dB(uV)]	[dB(uV)]	[dB(1/m)]	[dB(uV/m)]	[dB(uV/m)]	[dB(uV/m)]	[dB(uV/m)]	[dB]	[dB]	[cm]	[deg]
1	1003.125	Н	28.2	36.1	-7.0	21.2	29.1	56.0	76.0	34.8	46.9	100.0	96.0
2	1331.875	V	28.2	42.4	-5.7	22.5	36.7	56.0	76.0	33.5	39.3	100.0	154.9
3	1855.625	V	26.7	32.7	-2.2	24.5	30.5	56.0	76.0	31.5	45.5	100.0	131.0
4	1987.500	V	22.9	35.7	-1.6	21.3	34.1	56.0	76.0	34.7	41.9	100.0	141.4
5	2331.250	V	23.5	42.1	-0.8	22.7	41.3	56.0	76.0	33.3	34.7	100.0	69.5



6.3 Electrostatic Discharge

Test specification	EN 61000	0-4-2:2009									
Test level	$\square \text{ Air: } \pm \square \text{ HCP:}$	act: $\pm 6 \text{ kV}$ = 2 kV, $\pm 4 \text{ kV}$, $\pm 8 \text{ k'}$ $\pm 2 \text{ kV}$, $\pm 4 \text{ kV}$, $\pm 6 $ $\pm 2 \text{ kV}$, $\pm 4 \text{ kV}$, $\pm 6 $	kV								
Discharge impedance	330 Ω / 1	50 pF									
Number of discharge (Each polarity)	Conta	\Box Contact: 10 \boxtimes Air: 10 \boxtimes HCP / VCP: 10									
Interval between discharges	1 s										
Testing voltage	DC 12 V	, PoE									
Test facility	Shielded	room									
Date	2013.06.	19									
Temperature(°C)	26 °C	26 °C Humidity (% R.H.) 48 % R.H. Pressure (kPa) 99.5 kPa									
Remarks Complied - There was no change of operation status during above testing.											

6.3.1 Measurement procedure

A ground reference plane was located on the floor, and connected to earth via a low Impedance connection. The return cable of the ESD generator was connected to the reference plane. In case of floor standing equipment, EUT was placed on the reference plane on 0.1 m of insulating Support. In case of table top equipment, EUT was placed on a wooden table 0.8 m above the reference grounded floor. A horizontal coupling plane (HCP) was placed on the table, and Connected to the reference plane via a 470 k Ω resistor located in each end (0.5 mm insulating support between EUT and HCP). In both cases a vertical coupling plane(VCP) OF 0.5 X 0.5 m was located 0.1 m from the EUT's sides. The VCP was connected to the reference plane in the same matter as the HCP.

6.3.2 Used equipments

Equipment	Model No.	Serial No.	Makers	Next Cal. Date	Used
ESD Tester	PESD 1600	H011 309	HAEFELY	2013.07.18	
ESD Tester	NSG 437	182	TESEQ	2014.05.21	\boxtimes
НСР	-	-	-	-	
VCP	-	-	-	-	\boxtimes



6.3.3 Photographs of test setup

#1- DC 12V



#2-PoE

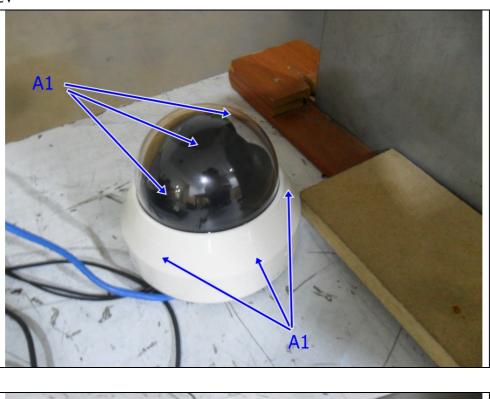


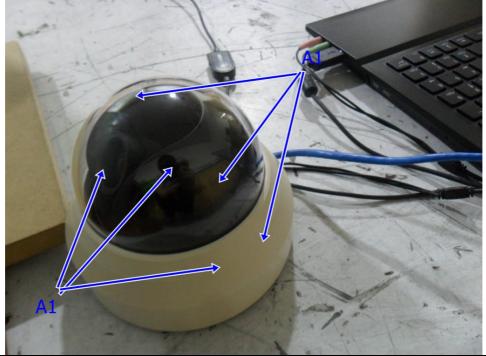


6.3.4 Measurement result Electrostatic Discharge (Test Point)

#1- DC 12V

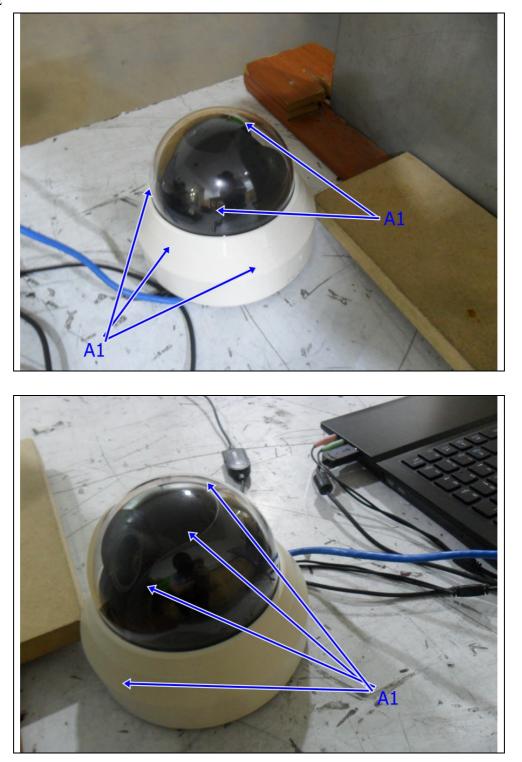
Air discharge







#2-PoE





#1- DC 12 V, #2- PoE

HCP/VCP discharge

Location(EUT)	Applied level (±)	Result
HCP (All 4 sides)	-	-
VCP (All 4 sides)	± 2 kV, ± 4 kV, ± 6 kV	Complied

Contact discharge

Location(EUT)		Applied level (±)	Result
-	-	-	-

Air discharge

Location(EUT)		Applied level (±)	Result
A1	Enclosure(Case)	± 2 kV, ± 4 kV, ± 8 kV	Complied



6.4 Radio Frequency Electromagnetic Fields

Test specification	EN 61000-4-3:2006+A2:2010					
Tested frequency	80 MHz ~ 1 GHz	80 MHz ~ 1 GHz, 1 GHz ~ 2.7 GHz				
Test level & Modulation	-	1 V/m, 3 V/m, 10 V/m, 80 % Amplitude Modulation (1 kHz) 1 V/m, 3 V/m, 10 V/m, Pulse Modulation (1 Hz (0.5 s ON: 0.5 s OFF))				
Frequency Step	log 1 % step					
Dwell time	3 s					
Distance	3 m from E	3 m from EUT to tip of antenna				
Testing Voltage	DC 12 V, PoE					
Test facility	Fully anechoi	Fully anechoic chamber (3 m)				
Date	2013. 06. 19					
Temperature(°C)	25 °C Humidity (% R.H.) 47 % R.H. Pressure (kPa) 99.5 kPa					
Remarks	Complied - There was no change of operation status during above testing.					

6.4.1 Measurement procedure

The test was performed at 3 m full anechoic chamber.

For floor standing equipment, the EUT was standing on the floor.

For tabletop equipment, the EUT was located on a wooden table 0.8 m above the floor.

The EUT was tested all sides, horizontal and vertical polarization.



6.4.2 Used equipments

Equipment	Model no.	Serial no.	Makers	Next Cal. date	Used
Power meter	PM2002	302852	AR	2014.04.05	\boxtimes
Power sensor	PH2000	303224	AR	2014.04.05	\boxtimes
Power sensor	PH2000	311217	AR	2014.04.05	\boxtimes
Directional coupler	DC6180	303976	AR	2014.04.08	\boxtimes
Directional coupler	DC7144M1	320279	AR	2014.02.07	\boxtimes
Signal generator	E4421B	GB40052295	AGILENT	2013.10.11	\boxtimes
Amplifier	BBA100	100996-1	R&S	2014.02.12	\boxtimes
Amplifier	60S1G3M2	320444	AR	2014.04.09	\boxtimes
Broadband Ant.	LPDA-0803	130269	ETS	-	\boxtimes
Fiber Optic Modem	HI-4413P	-	ETS- LINDGREM	-	\boxtimes
Antenna master	_	-	ETS	_	\boxtimes

6.4.3 Photographs of test setup

#1- DC 12 V





#2- PoE



6.4.4 Measurement result

#1- DC 12	V, #2- PoE
	,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,

Location(EUT)	Antenna polarization	Result	
Front side	Horizontal	Complied	
From side	Vertical	Complied	
Rear side	Horizontal	Complied	
Rear side	Vertical	Complied	
T C 1	Horizontal	Complied	
Left side	Vertical	Complied	
Right side	Horizontal	Complied	
	Vertical	Complied	



6.5 Electric Fast Transient/BURST

Test specification	EN 61000-4-4:2004+A1:2010					
	🖾 DC 12 V					
Coupling	Signal: Clamp					
	Telecommunication: Clamp					
	\square DC 12 V: ± 1 kV Peak					
Test level	\Box Signal/Control: ± 1 kV Peak					
	\square Telecommunication: ± 1 kV Peak					
Repetition frequency	100 kHz, $Tr/Th = 5 / 50$ ns					
Coupling time	60 s					
Testing Voltage	DC 12 V, PoE					
Test facility	Shielded room					
Date	2013. 06. 18					
Temperature(°C)	24 °C Humidity (% R.H.) 44 % R.H. Pressure (kPa) 99.0 kPa					
Remarks	Complied - There was no change of operation status during above testing.					

6.5.1 Measurement procedure

A ground reference plane was located on the floor.

EFT generator was connected to reference ground plane via low impedance connection.

For floor standing equipment, EUT was placed on a 0.1 m wooden table.

For tabletop equipment, EUT was placed on a 0.1 m above the ground reference plane. Test generator and coupling/decoupling network was placed on, and bounded to, the ground reference plane. When using the coupling clamp, the minimum distance between the coupling plates and all other conductive surfaces, except the ground reference plane beneath the coupling clamp, Shall be 0.5 m.

6.5.2 Used equipments

Equipment	Model No.	Serial No.	Makers	Next Cal. date	Used
Ultra compact simulator	UCS 500 M6	V0545100858	EM TEST	2014.01.31	\boxtimes
Ultra compact simulator	UCS 500 M6	0701-03	EM TEST	2014.06.21	
Capacitive Coupling Clamp	-	-	EM TEST	-	\boxtimes



6.5.3 Photographs of test setup

#1- DC 12 V







#2- PoE



6.5.4 Measurement result

* DC Line (#1- DC 12 V)

EFT coupling point	(+)	(-)	Result
DC 12 V	+ 1 kV	- 1 kV	Complied

* Signal/Control

EFT coupling point	(+)	(-)	Result
-	-	-	-

* Telecommunication (#1- DC 12 V, #2- PoE)

EFT coupling point	(+)	(-)	Result
LAN(RJ-45)	+ 1 kV	- 1 kV	Complied
LAN(PoE)	+ 1 kV	- 1 kV	Complied



6.6 Surge

Test specification	EN 61000-4-5:2006			
Coupling	DC 12 V: CDN Signal/Control: CDN			
Test level				
Coupling Impedance	$\Box \text{ Differential mode: 18 } \mu F \qquad \Box \text{ Common mode: 10 } \Omega + 9 \ \mu F \\ \boxtimes 40 \ \Omega + 0.5 \ \mu F \qquad \Box \text{ Direct}$			
Surge pulse shape	$Tr/Th = 1.2 / 50 \ \mu s$			
Number of surge	5			
Coupling time	1 min			
Testing Voltage	DC 12 V			
Test facility	Shielded room			
Date	2013. 06. 18			
Temperature(°C)	24 °C Humidity (% R.H.) 44 % R.H. Pressure (kPa) 99.0 kPa			
Remarks	Complied - There was no change of operation status during above testing.			

6.6.1 Measurement procedure

A ground reference plane was located on the floor. SURGE generator was connected to reference ground plane via low impedance connection. For floor standing equipment & table top equipment, EUT was placed on a wooden table.

6.6.2 Used equipments

Equipment	Model No.	Serial No.	Makers	Next Cal. date	Used
Ultra compact simulator	UCS 500 M6	V0545100858	EM TEST	2014.01.31	\boxtimes
Ultra compact simulator	UCS 500 M6	0701-03	EM TEST	2014.06.21	
CDN	CNV 508 N1	V1108108861	EM TEST	2014.01.03	



6.6.3 Photographs of test setup

#1- DC 12 V



6.6.4 Measurement result

* DC Line (#1- DC 12 V)

Coupling point	(+)	(-)	Result
DC 12 V	+ 0.5 kV, + 1 kV	- 0.5 kV, - 1 kV	Complied

* Signal/Control

Coupling point	(+)	(-)	Result
-	-	-	-



6.7 Conducted Immunity

Test specification	EN 61000-4-6:2009			
Tested frequency	0.15 MHz ~ 100 MHz			
Test level & Modulation	1 V, 3 V, 10 V, 80 % Amplitude Modulation (1 kHz) 1 V, 3 V, 10 V, Pulse Modulation (1 Hz (0.5 s ON: 0.5 s OFF))			
Frequency Step	log 1 % step			
Coupling method	 ☑ DC 12 V: CDN(M2) □ Signal/Control: Clamp ☑ Telecommunication: Clamp 			
Testing Voltage	DC 12 V, PoE			
Test facility	Shielded room			
Date	2013. 06. 18			
Temperature(°C)	24 °C Humidity (% R.H.) 44 % R.H. Pressure (kPa) 99.0 kPa			
Remarks	Complied - There was no change of operation status during above testing.			

6.7.1 Measurement procedure

A ground reference plane was located on the floor.

The test was performed on a ground reference plane on a 0.1 m wooden table. This test were Performed using CDN for mains, clamp for signal and injection probe. The frequency range was swept from 0.15 MHz to 100 MHz. This frequency range was Modulated with 1 kHz sine wave at 80 %. The signal generators provided the modulated frequency at a 1 % step size.

The power and all network cable, I/O cables longer than 3 $\,$ m length were tested.

6.7.2 Used equipments

Equipment	Model no.	Serial no.	Makers	Next Cal. date	Used
CS generator	CWS 500	V0635101750	EM TEST	2014.01.17	\square
CS generator	CWS500N1	V1041107702	EM TEST	2013.11.01	
CDN	CDN L-801 M2/M3	2936	EM TEST	2014.02.06	\square
CDN	CDN M2/M3	0906-12	EM TEST	2013.10.11	\square
Attenuator	73-6-34	MU918	MCE/WEINSCHEL	2013.10.11	\square
EM Clamp	KEMZ 801	17643	Schaffner	2014.04.17	\square
CDN	CDN S1/75	0410-28	EM TEST	2014.05.13	



6.7.3 Photographs of test setup

#1- DC 12 V







#2- PoE



6.7.4 Measurement result

* DC Line (#1- DC 12 V)

Coupling point	Coupling method	Result
DC 12 V	CDN(M2)	Complied

* Signal/Control

Coupling point	Coupling method	Result
-	-	-

* Telecommunication (#1- DC 12 V, #2- PoE)

Coupling point	Coupling method	Result
LAN(RJ-45)	Clamp	Complied
LAN(PoE)	Clamp	Complied



7. E.U.T. photographs

Front View



Rear View





Left View

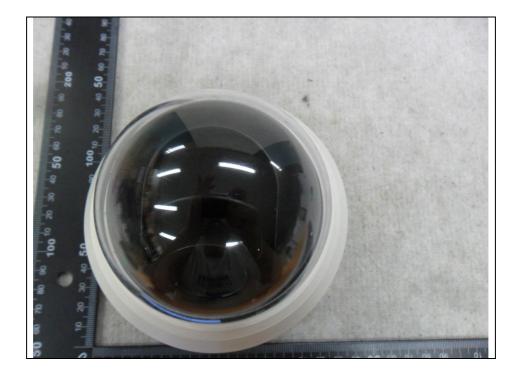


Right View





Top View

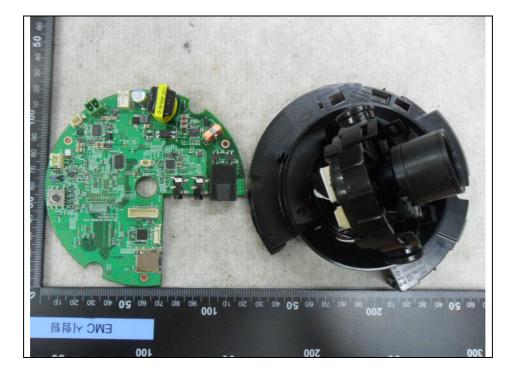


Bottom View





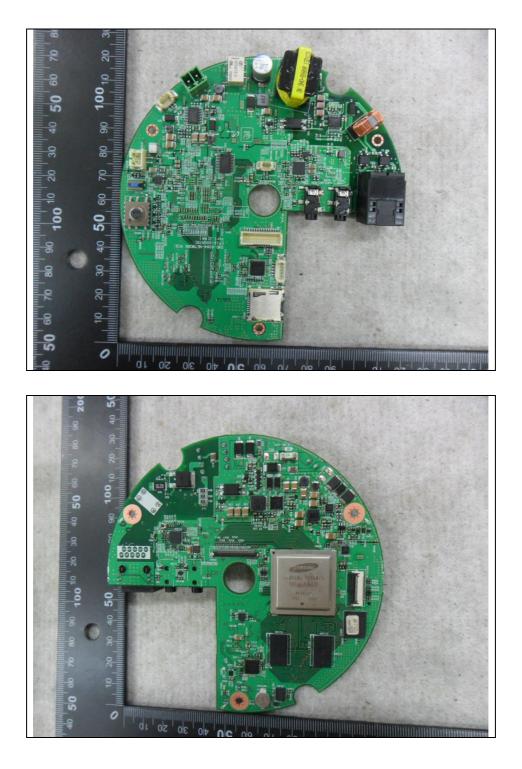
Inside





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Main Board





CCD Board

